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| <p style="text-align: center;">         LIST OF PATENTS AND<br/>         PUBLICATIONS<br/>         FOR APPLICANT'S INFORMATION<br/>         DISCLOSURE STATEMENT       </p> <p style="text-align: right; font-size: small;">         OIPE SCITY<br/>         JAN 21 2002<br/>         PATENT &amp; TRADEMARK OFFICE       </p> | ATTORNEY DOCKET NO.         | SERIAL NO.      |
|                                                                                                                                                                                                                                                                                                                                | SP00-314                    | 09/943,252      |
|                                                                                                                                                                                                                                                                                                                                | APPLICANT Best et al.       |                 |
|                                                                                                                                                                                                                                                                                                                                | FILING DATE August 30, 2001 | GROUP 2872 1731 |

**REFERENCE DESIGNATION**

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|                  | AA 5,315,629    | 5/24/94 | Jewell et al. | 378   | 34        |                        |
| SV               | AB 6,280,294    | 8/28/01 | Miyamoto      | 451   | 34        | <del>✓</del>           |
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| AD               |                 |         |               |       |           |                        |
| AE               |                 |         |               |       |           |                        |
| AF               |                 |         |               |       |           |                        |
| AG               |                 |         |               |       |           |                        |
| AH               |                 |         |               |       |           |                        |
| AI               |                 |         |               |       |           |                        |
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|    | Document Number | Date | Country | Class | Sub-Class | Translat Yes |
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Information Disclosure Statement-PTO-1449 (Modified)

LIST OF PATENTS AND  
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APPLICANT

Best et al

FILING DATE

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| SV               | AD | 4,282,021       | 8/4/81   | Mazeau et al.    |       |           |                        |
| SV               | AE | 5,750,448       | 5/12/98  | Grabowski et al. |       |           |                        |
|                  | AF |                 |          |                  |       |           |                        |
|                  | AG |                 |          |                  |       |           |                        |
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| FORM PTO-1449 (MODIFIED)                                                                                                                                                                                                    |  | ATTORNEY DOCKET NO.          | SERIAL NO.                         |
| <p style="text-align: center;">LIST OF PATENTS AND<br/>PUBLICATIONS<br/>FOR APPLICANTS INFORMATION<br/>DISCLOSURE STATEMENT</p> <p style="text-align: right;">O I P E<br/>JAN 22 2002<br/>PATENT &amp; TRADEMARK OFFICE</p> |  | SP00-314                     | 02943,252                          |
|                                                                                                                                                                                                                             |  | APPLICANT: Best et al.       | RECEIVED<br>APR 03 2002<br>TG 1700 |
|                                                                                                                                                                                                                             |  | FILING DATE: August 30, 2001 | GROUP: 2872 / 731                  |

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| SV               | AE | 4,344,816       | 8/17/82  | Craighead et al.   | 156   | 643       |                        |
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| SV               | AM | 5,146,482       | 9/8/92   | Hoover             | 378   | 43        |                        |
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|                                                                                                                       | APPLICANT Best et al.           |                          |
|                                                                                                                       | FILING DATE August 30, 2001     | GROUP: 2872 / 731        |

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| SV                                                | AJ1             | 5,737,137             | 4/7/98   | Cohen et al.       | 359             | 859                    |  |
| SV                                                | AK1             | 5,815,310             | 9/29/98  | Williamson         | 359             | 365                    |  |
| SV                                                | AL1             | 5,868,605             | 2/9/99   | Cesna              | 451             | 41                     |  |
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PATENT & TRADEMARK OFFICE

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